

Search Notes	Application/Control No.	Applicant(s)/Patent Under Reexamination
	10574600	AKAHORI ET AL.
	Examiner	Art Unit
	Baker, David S	2884

SEARCHED

Class	Subclass	Date	Examiner
250	336.1	21 JUL 08	DSB
250	370.01	21 JUL 08	DSB
250	370.14	21 JUL 08	DSB

SEARCH NOTES

Search Notes	Date	Examiner
See attached EAST Search History	21 JUL 08	DSB
Consultation: Examiner Christine Sung AU 2884	21 JUL 08	DSB

INTERFERENCE SEARCH

Class	Subclass	Date	Examiner
ALL	ALL; Search Terms: "(voltage WITH divid\$3).clm. AND resistor.clm. AND serial\$3.clm. AND semiconductor.clm. AND electrode.clm."	21 JUL 08	DSB
250	ALL; Search Terms: "(voltage WITH divid\$3).clm. AND resistor.clm. AND serial\$3.clm. AND semiconductor.clm. AND electrode.clm."	21 JUL 08	DSB
378	ALL; Search Terms: "(voltage WITH divid\$3).clm. AND resistor.clm. AND serial\$3.clm. AND semiconductor.clm. AND electrode.clm."	21 JUL 08	DSB
600	ALL; Search Terms: "(voltage WITH divid\$3).clm. AND resistor.clm. AND serial\$3.clm. AND semiconductor.clm. AND electrode.clm."	21 JUL 08	DSB